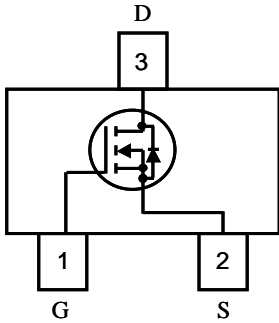




## N-Channel Enhancement Mode Field Effect Transistor

<p>● <b>Features</b></p> <p><math>V_{DS}(V) = 20V, I_D = 2.2A,</math>  <math>R_{DS(ON)} = 75m\Omega @V_{GS} = 4.5V.</math>  <math>R_{DS(ON)} = 90m\Omega @V_{GS} = 2.5V.</math>          Advanced trench process technology          High-density cell design for ultra low on-resistance          Compact and low profile SOT23 package</p>	<p>● <b>General Description</b></p> <p>This N-Channel enhancement mode power FETs are produced with high cell density, DMOS trench technology, which is especially used to minimize on-state resistance. This device is particularly suited for low voltage application such as portable equipment, power management and other battery powered circuits, and low in-line power dissipation are needed in a very small outline surface mount package. Excellent thermal and electrical capabilities.</p>
<p>● <b>Pin Configurations</b></p> <div style="text-align: center;">  <p><b>SOT23</b></p> </div>	

● **Absolute Maximum Ratings** @ $T_A=25^\circ C$  unless otherwise noted

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		$V_{DSS}$	20	V
Gate-Source Voltage		$V_{GSS}$	$\pm 10$	V
Drain Current	Continuous	$I_D$	2.2	A
	Pulsed		10	
Power Dissipation		$P_D$	350	mW
Operating and Storage Junction Temperature Range		$T_J, T_{STG}$	-55 to +150	$^\circ C$



● Electrical Characteristics @ $T_A=25^{\circ}\text{C}$  unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain–Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 10\mu\text{A}$	20	--	--	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	$\mu\text{A}$
Gate–Body Leakage	$I_{GSS}$	$V_{GS} = \pm 8\text{ V}, V_{DS} = 0\text{ V}$	--	--	$\pm 100$	nA
<b>ON CHARACTERISTICS<sup>(1)</sup></b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 50\mu\text{A}$	0.4	0.75	2.0	V
Static Drain–Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 4.5\text{ V}, I_D = 3.6\text{ A}$	--	70	85	$\text{m}\Omega$
		$V_{GS} = 2.5\text{ V}, I_D = 3.1\text{ A}$	--	90	115	
Forward Transconductance	$g_{FS}$	$V_{DS} = 5\text{ V}, I_D = 3.6\text{ A}$	2	7.7	14	S
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 10\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	450	--	$\text{pF}$
Output Capacitance	$C_{oss}$		--	70	--	
Reverse Transfer Capacitance	$C_{rss}$		--	43	--	
<b>SWITCHING CHARACTERISTICS</b>						
Turn–On Delay Time	$t_{d(on)}$	$V_{DD} = 5\text{ V}, I_D = 3.6\text{ A},$ $V_{GS} = 4.5\text{ V}, R_{GEN} = 6\Omega$	--	--	15	$\text{nS}$
Turn–On Rise Time	$t_r$		--	--	80	
Turn–Off Delay Time	$t_{d(off)}$		--	--	60	
Turn–Off Fall Time	$t_f$		--	--	25	
<b>DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS</b>						
Diode Forward Voltage <sup>(1)</sup>	$V_{SD}$	$V_{GS} = 0\text{ V}, I_S = 1.1\text{ A}$	0.6	0.8	1.15	V

Notes :

(1).Pulse Test : Pulse Width < 300 $\mu\text{s}$ , Duty Cycle < 2%.

(2).Surface Mounted on FR4 Board, t < 10 sec.



● Typical Performance Characteristics

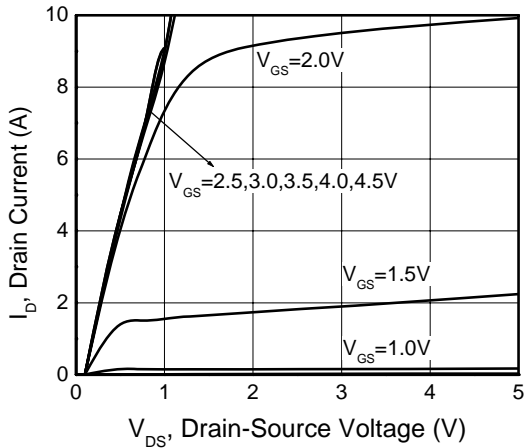


Figure 1. Output Characteristics

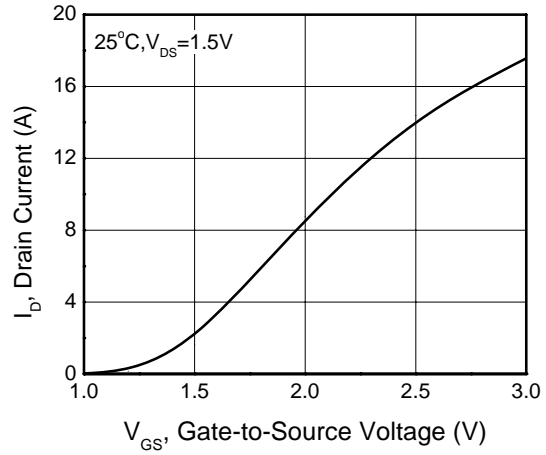


Figure 2. Transfer Characteristics

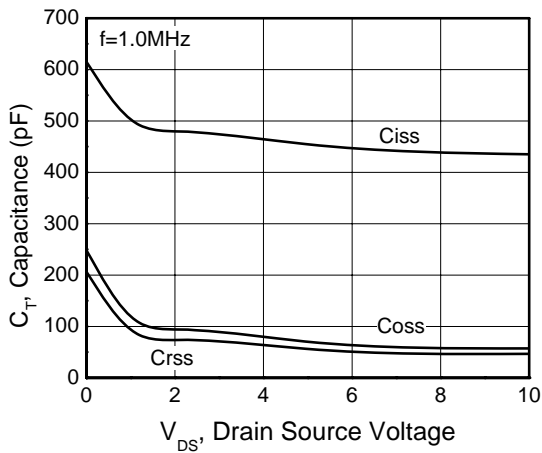


Figure 3. Capacitance

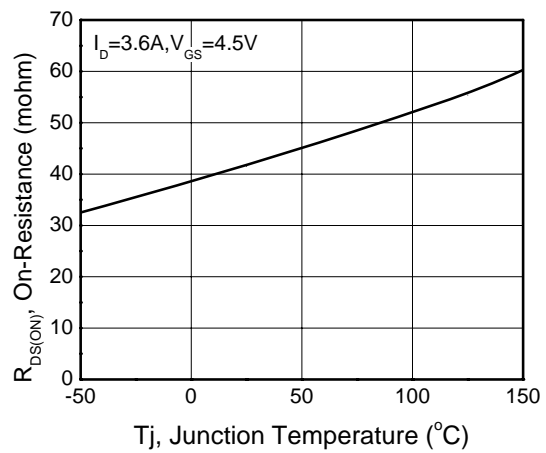


Figure 4. On-Resistance vs. Temperature

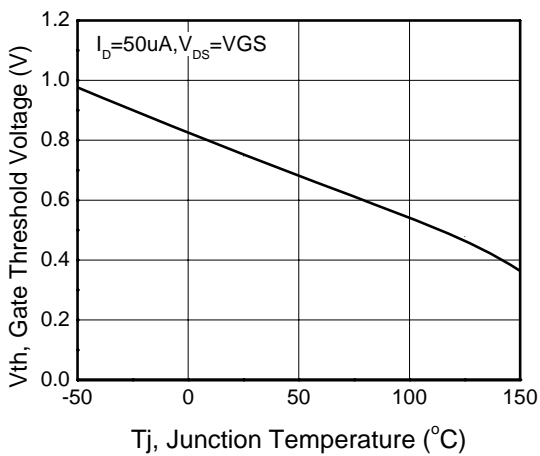


Figure 5. Gate Threshold Vs. Temperature

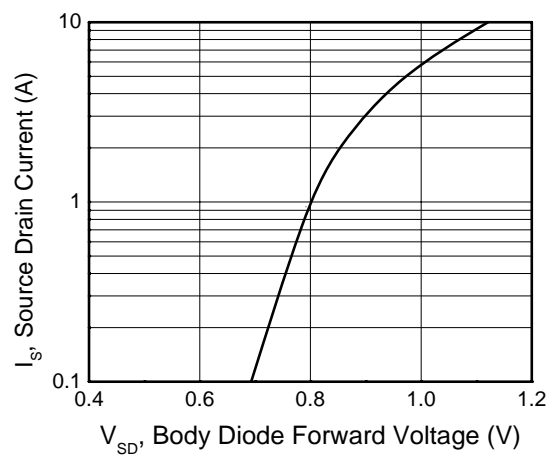


Figure 6. Body Diode Forward Voltage vs. Source Current

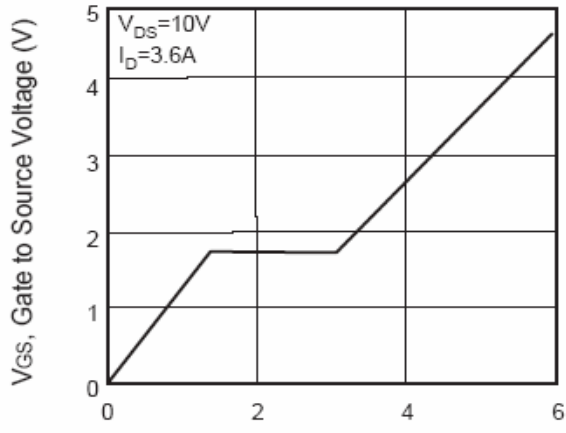


Figure 7. Gate Charge

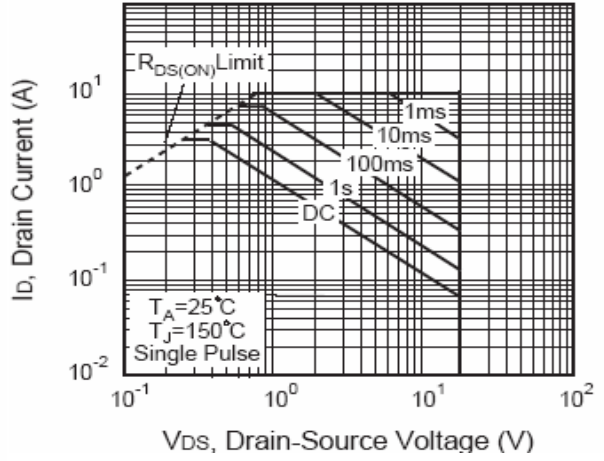
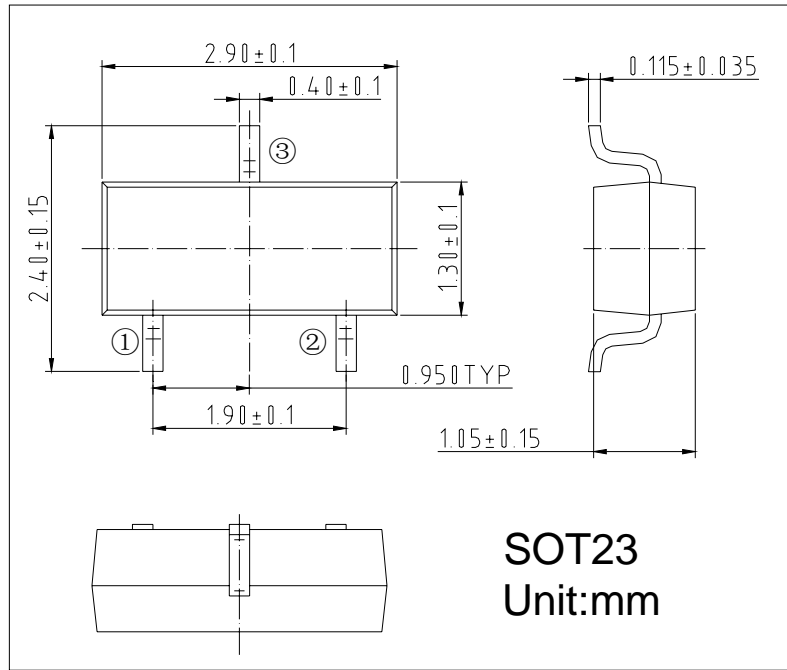


Figure 8. Maximum Safe Operating Area



Package Information



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